

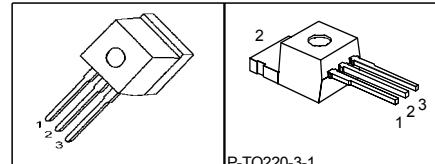
## Cool MOS™ Power Transistor

### Feature

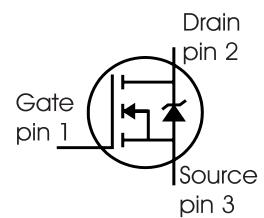
- New revolutionary high voltage technology
- Ultra low gate charge
- Periodic avalanche rated
- Extreme dv/dt rated
- Ultra low effective capacitances
- Improved transconductance
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>0)</sup> for target applications

$V_{DS}$	600	V
$R_{DS(on)}$	0.38	$\Omega$
$I_D$	11	A

PG-T0262      PG-T0220



Type	Package	Ordering Code	Marking
SPP11N60S5	PG-T0220	Q67040-S4198	11N60S5
SPI11N60S5	PG-T0262	Q67040-S4338	11N60S5



### Maximum Ratings

Parameter	Symbol	Value	Unit
Continuous drain current $T_C = 25^\circ\text{C}$	$I_D$	11	A
$T_C = 100^\circ\text{C}$		7	
Pulsed drain current, $t_p$ limited by $T_{jmax}$	$I_{D \text{ puls}}$	22	
Avalanche energy, single pulse $I_D = 5.5 \text{ A}, V_{DD} = 50 \text{ V}$	$E_{AS}$	340	mJ
Avalanche energy, repetitive $t_{AR}$ limited by $T_{jmax}$ <sup>1)</sup> $I_D = 11 \text{ A}, V_{DD} = 50 \text{ V}$	$E_{AR}$	0.6	
Avalanche current, repetitive $t_{AR}$ limited by $T_{jmax}$	$I_{AR}$	11	A
Gate source voltage	$V_{GS}$	$\pm 20$	V
Gate source voltage AC ( $f > 1\text{Hz}$ )	$V_{GS}$	$\pm 30$	
Power dissipation, $T_C = 25^\circ\text{C}$	$P_{tot}$	125	W
Operating and storage temperature	$T_j, T_{stg}$	-55... +150	°C

**Maximum Ratings**

Parameter	Symbol	Value	Unit
Drain Source voltage slope $V_{DS} = 480 \text{ V}$ , $I_D = 11 \text{ A}$ , $T_j = 125^\circ\text{C}$	$dv/dt$	20	V/ns

**Thermal Characteristics**

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Thermal resistance, junction - case	$R_{thJC}$	-	-	1	K/W
Thermal resistance, junction - ambient, leaded	$R_{thJA}$	-	-	62	
SMD version, device on PCB: @ min. footprint @ 6 cm <sup>2</sup> cooling area <sup>2)</sup>	$R_{thJA}$			62	
Soldering temperature, wavesoldering 1.6 mm (0.063 in.) from case for 10s	$T_{sold}$	-	-	260	°C

**Electrical Characteristics, at  $T_j=25^\circ\text{C}$  unless otherwise specified**

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0\text{V}$ , $I_D=0.25\text{mA}$	600	-	-	V
Drain-Source avalanche breakdown voltage	$V_{(BR)DS}$	$V_{GS}=0\text{V}$ , $I_D=11\text{A}$	-	700	-	
Gate threshold voltage	$V_{GS(th)}$	$I_D=500\mu\text{A}$ , $V_{GS}=V_{DS}$	3.5	4.5	5.5	
Zero gate voltage drain current	$I_{DSS}$	$V_{DS}=600\text{V}$ , $V_{GS}=0\text{V}$ , $T_j=25^\circ\text{C}$ , $T_j=150^\circ\text{C}$	-	-	25	$\mu\text{A}$
			-	-	250	
Gate-source leakage current	$I_{GSS}$	$V_{GS}=20\text{V}$ , $V_{DS}=0\text{V}$	-	-	100	
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}$ , $I_D=7\text{A}$ , $T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$	-	0.34	0.38	$\Omega$
			-	0.92	-	
Gate input resistance	$R_G$	f=1MHz, open Drain	-	29	-	

**Electrical Characteristics , at  $T_j = 25^\circ\text{C}$ , unless otherwise specified**

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
<b>Characteristics</b>						
Transconductance	$g_{fs}$	$V_{DS} \geq 2 * I_D * R_{DS(on)max}$ , $I_D = 7\text{A}$	-	6	-	S
Input capacitance	$C_{iss}$	$V_{GS}=0\text{V}$ , $V_{DS}=25\text{V}$ , $f=1\text{MHz}$	-	1460	-	pF
Output capacitance	$C_{oss}$		-	610	-	
Reverse transfer capacitance	$C_{rss}$		-	21	-	
Effective output capacitance, <sup>3)</sup> energy related	$C_{o(er)}$	$V_{GS}=0\text{V}$ , $V_{DS}=0\text{V to } 480\text{V}$	-	45	-	pF
Effective output capacitance, <sup>4)</sup> time related	$C_{o(tr)}$		-	85	-	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=350\text{V}$ , $V_{GS}=0/10\text{V}$ , $I_D=11\text{A}$ , $R_G=6.8\Omega$	-	130	-	ns
Rise time	$t_r$		-	35	-	
Turn-off delay time	$t_{d(off)}$		-	150	225	
Fall time	$t_f$		-	20	30	

**Gate Charge Characteristics**

Gate to source charge	$Q_{gs}$	$V_{DD}=350\text{V}$ , $I_D=11\text{A}$	-	10.5	-	nC
Gate to drain charge	$Q_{gd}$		-	24	-	
Gate charge total	$Q_g$	$V_{DD}=350\text{V}$ , $I_D=11\text{A}$ , $V_{GS}=0$ to $10\text{V}$	-	41.5	54	
Gate plateau voltage	$V_{(plateau)}$	$V_{DD}=350\text{V}$ , $I_D=11\text{A}$	-	8	-	V

<sup>0</sup>J-STD20 and JESD22

<sup>1</sup>Repetitive avalanche causes additional power losses that can be calculated as  $P_{AV}=E_{AR}*f$ .

<sup>2</sup>Device on 40mm\*40mm\*1.5mm epoxy PCB FR4 with 6cm<sup>2</sup> (one layer, 70 µm thick) copper area for drain connection. PCB is vertical without blown air.

<sup>3</sup> $C_{o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

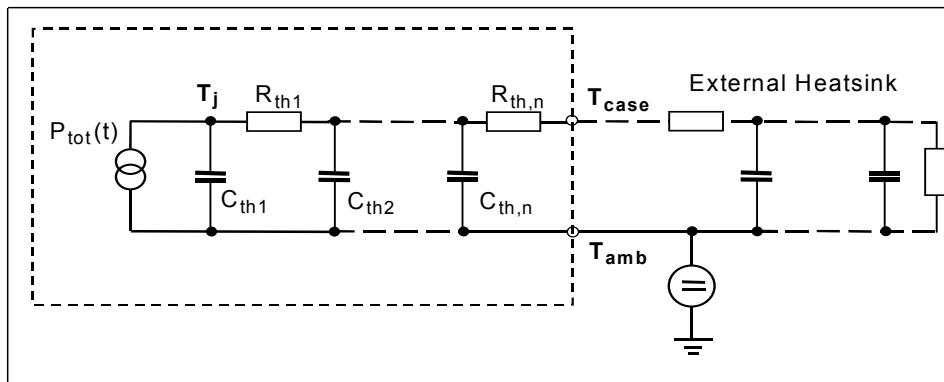
<sup>4</sup> $C_{o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Inverse diode continuous forward current	$I_S$	$T_C=25^\circ\text{C}$	-	-	11	A
Inverse diode direct current, pulsed	$I_{SM}$		-	-	22	
Inverse diode forward voltage	$V_{SD}$	$V_{GS}=0\text{V}$ , $I_F=I_S$	-	1	1.2	V
Reverse recovery time	$t_{rr}$	$V_R=350\text{V}$ , $I_F=I_S$ , $dI_F/dt=100\text{A}/\mu\text{s}$	-	650	1105	ns
Reverse recovery charge	$Q_{rr}$		-	7.9	-	$\mu\text{C}$

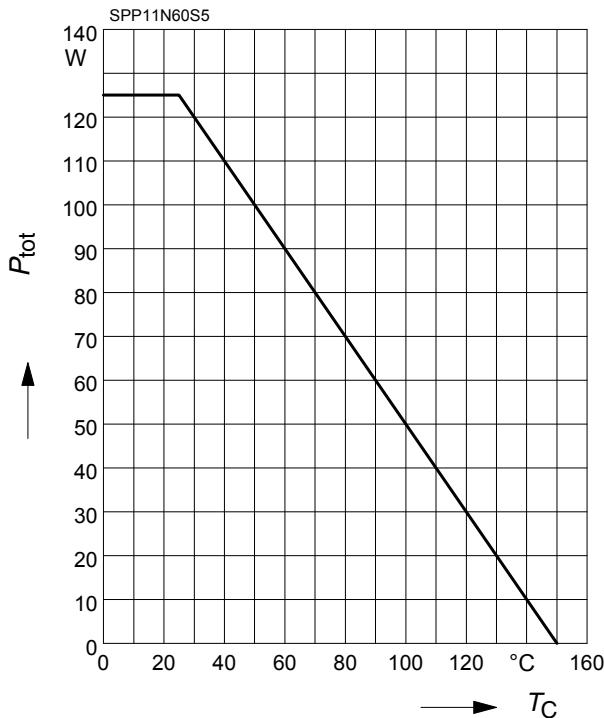
**Typical Transient Thermal Characteristics**

Symbol	Value	Unit	Symbol	Value	Unit
Thermal resistance			Thermal capacitance		
$R_{th1}$	0.015	K/W	$C_{th1}$	0.0001878	Ws/K
$R_{th2}$	0.03		$C_{th2}$	0.0007106	
$R_{th3}$	0.056		$C_{th3}$	0.000988	
$R_{th4}$	0.197		$C_{th4}$	0.002791	
$R_{th5}$	0.216		$C_{th5}$	0.007285	
$R_{th6}$	0.083		$C_{th6}$	0.063	



### 1 Power dissipation

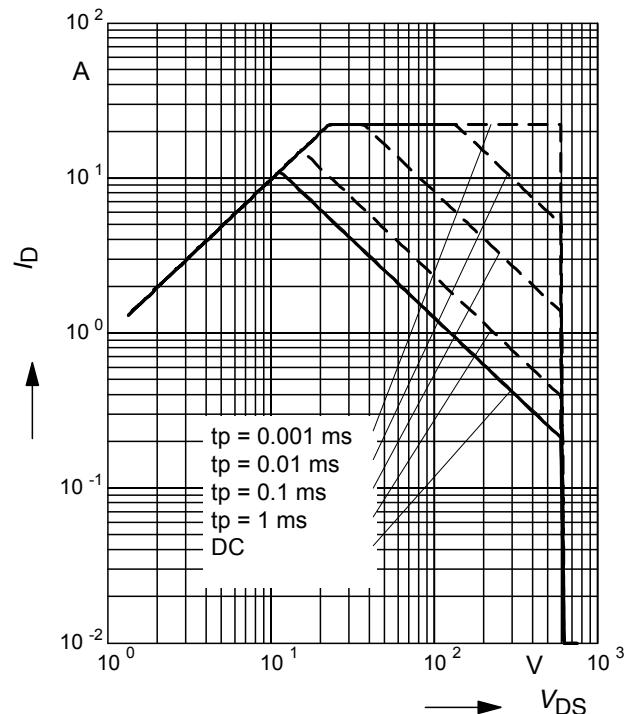
$$P_{\text{tot}} = f(T_C)$$



### 2 Safe operating area

$$I_D = f(V_{DS})$$

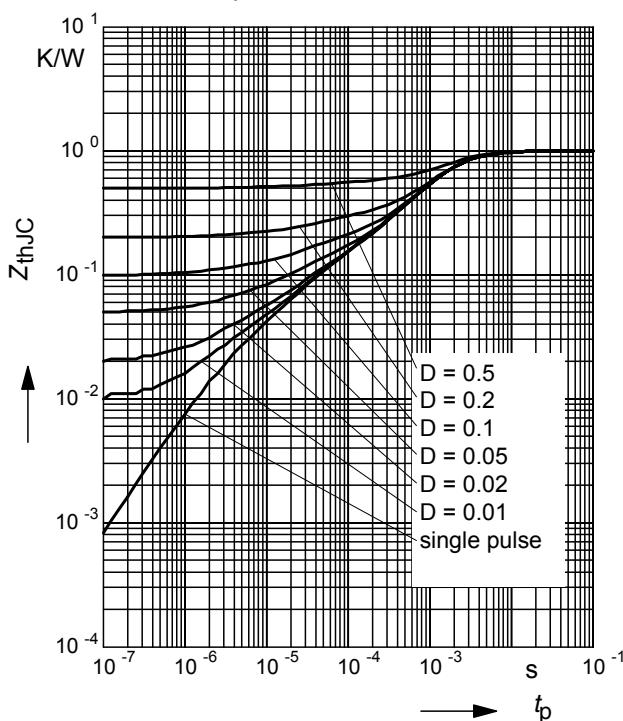
parameter :  $D = 0$  ,  $T_C=25^\circ\text{C}$



### 3 Transient thermal impedance

$$Z_{\text{thJC}} = f(t_p)$$

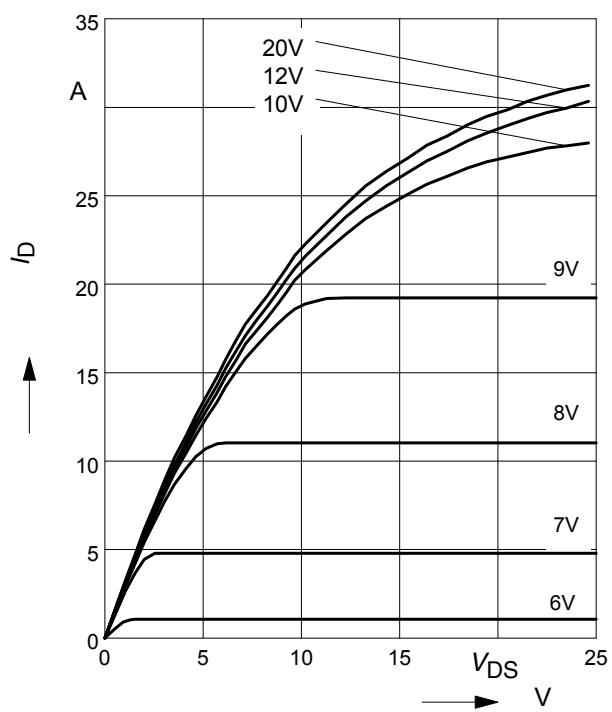
parameter:  $D = t_p/T$



### 4 Typ. output characteristic

$$I_D = f(V_{DS}); \quad T_j=25^\circ\text{C}$$

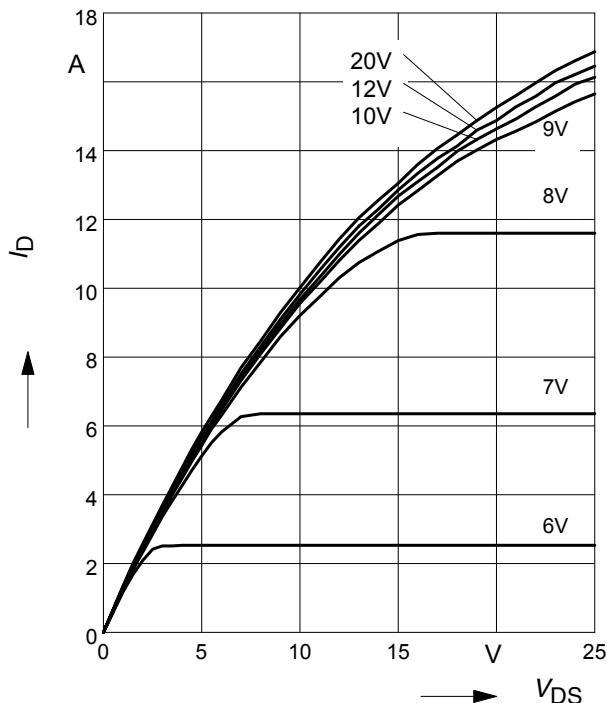
parameter:  $t_p = 10 \mu\text{s}$ ,  $V_{GS}$



### 5 Typ. output characteristic

$I_D = f(V_{DS})$ ;  $T_j=150^\circ\text{C}$

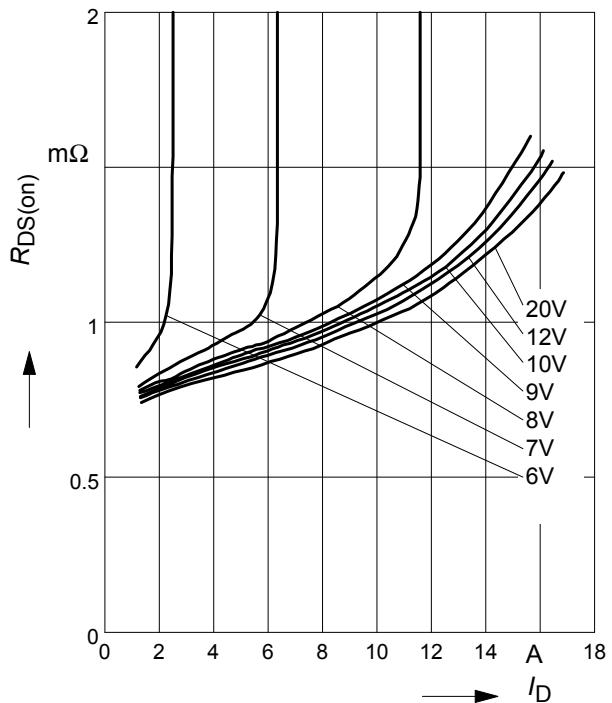
parameter:  $t_p = 10 \mu\text{s}$ ,  $V_{GS}$



### 6 Typ. drain-source on resistance

$R_{DS(on)} = f(I_D)$

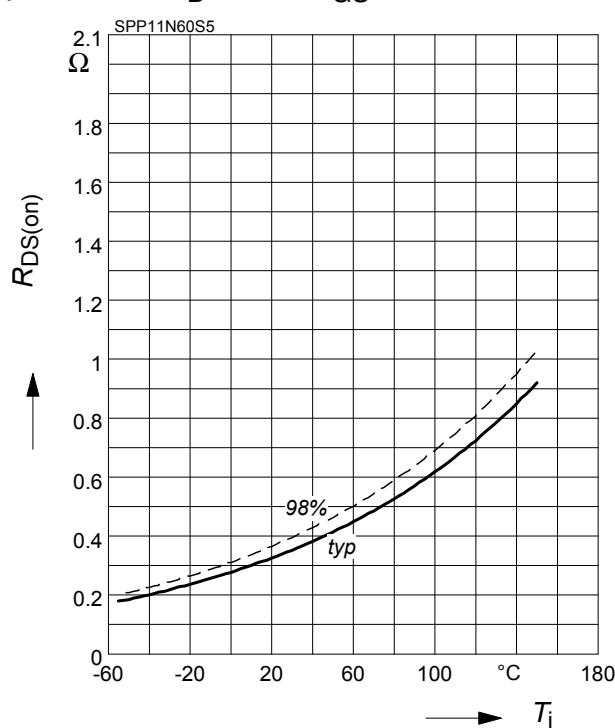
parameter:  $T_j=150^\circ\text{C}$ ,  $V_{GS}$



### 7 Drain-source on-state resistance

$R_{DS(on)} = f(T_j)$

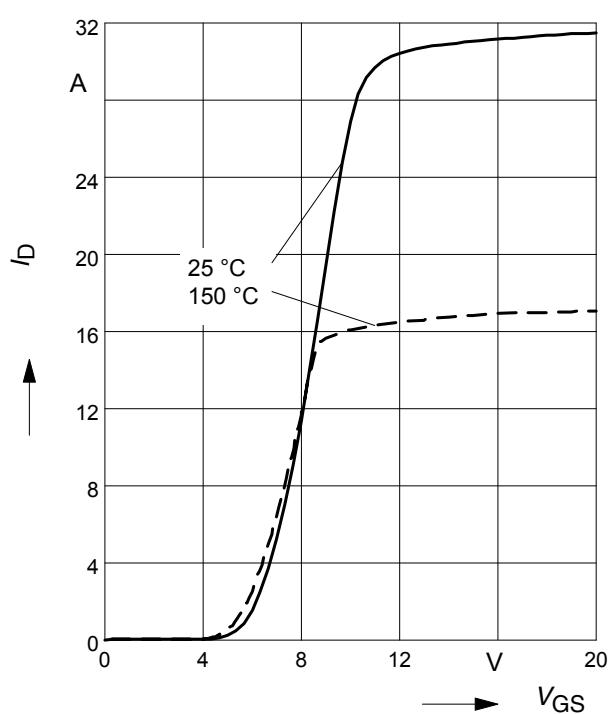
parameter :  $I_D = 7 \text{ A}$ ,  $V_{GS} = 10 \text{ V}$



### 8 Typ. transfer characteristics

$I_D = f( V_{GS} )$ ;  $V_{DS} \geq 2 \times I_D \times R_{DS(on)\max}$

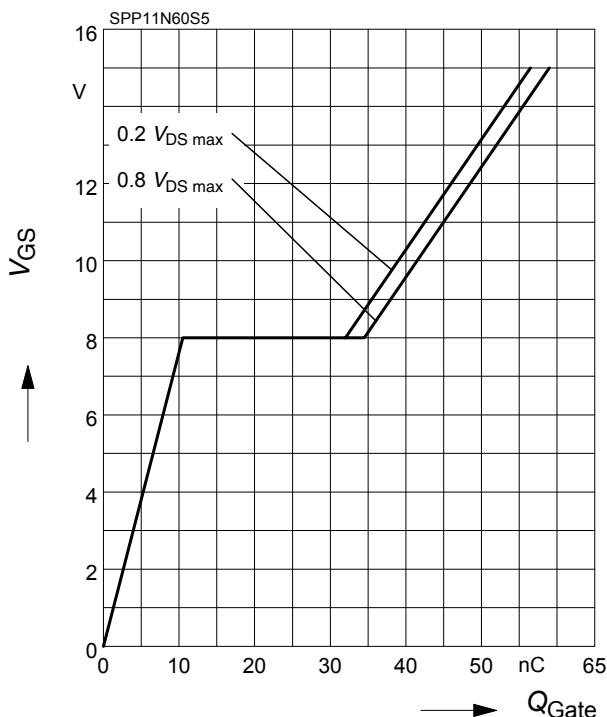
parameter:  $t_p = 10 \mu\text{s}$



### 9 Typ. gate charge

$$V_{GS} = f(Q_{Gate})$$

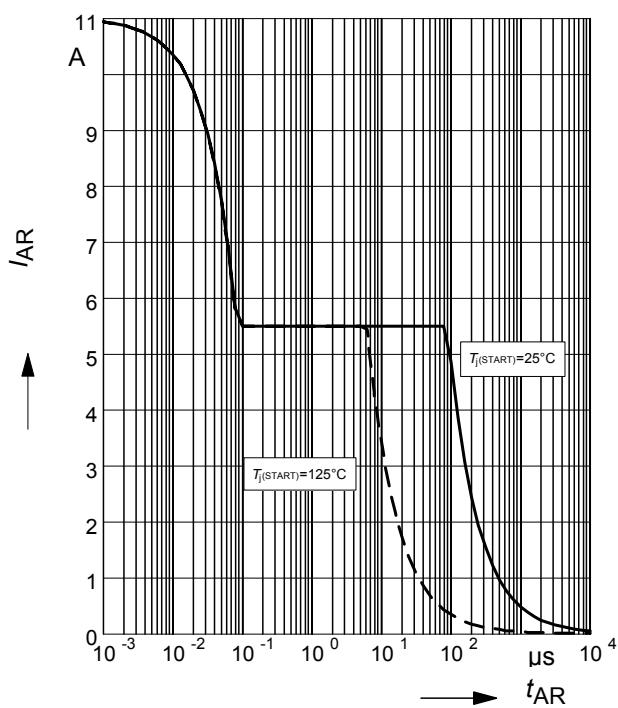
parameter:  $I_D = 11 \text{ A pulsed}$



### 11 Avalanche SOA

$$I_{AR} = f(t_{AR})$$

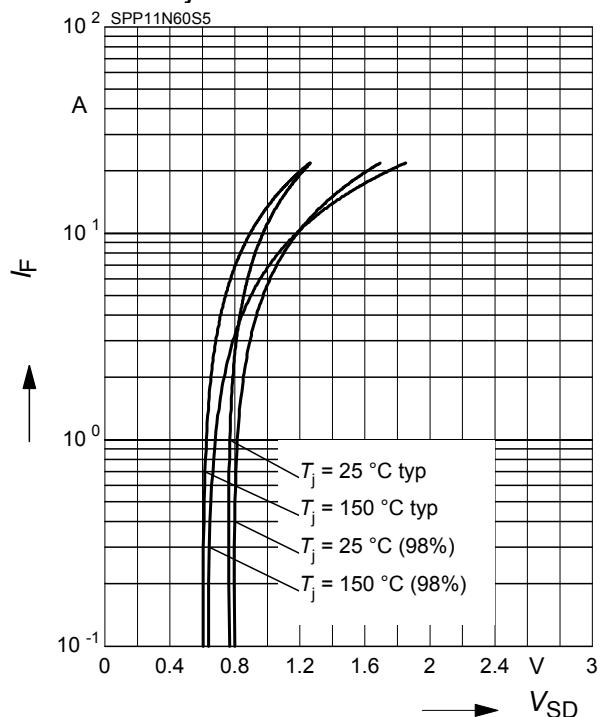
par.:  $T_j \leq 150 \text{ }^\circ\text{C}$



### 10 Forward characteristics of body diode

$$I_F = f(V_{SD})$$

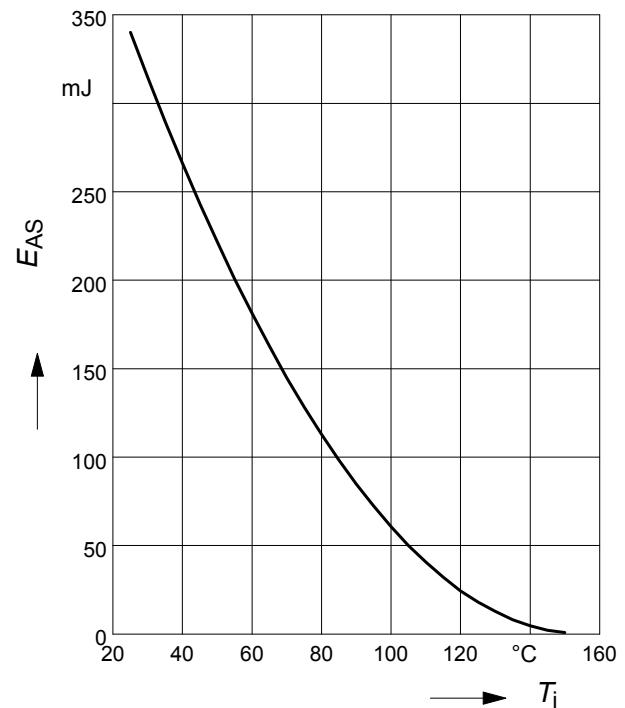
parameter:  $T_j, t_p = 10 \mu\text{s}$



### 12 Avalanche energy

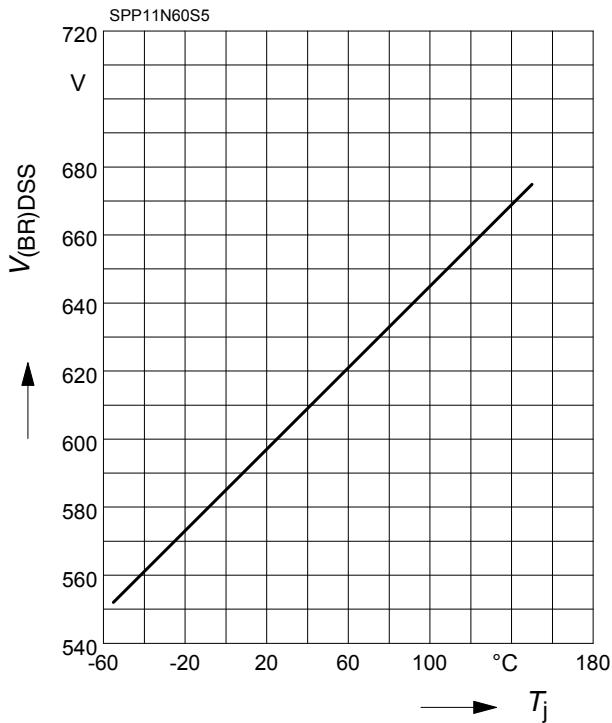
$$E_{AS} = f(T_j)$$

par.:  $I_D = 5.5 \text{ A}, V_{DD} = 50 \text{ V}$



### 13 Drain-source breakdown voltage

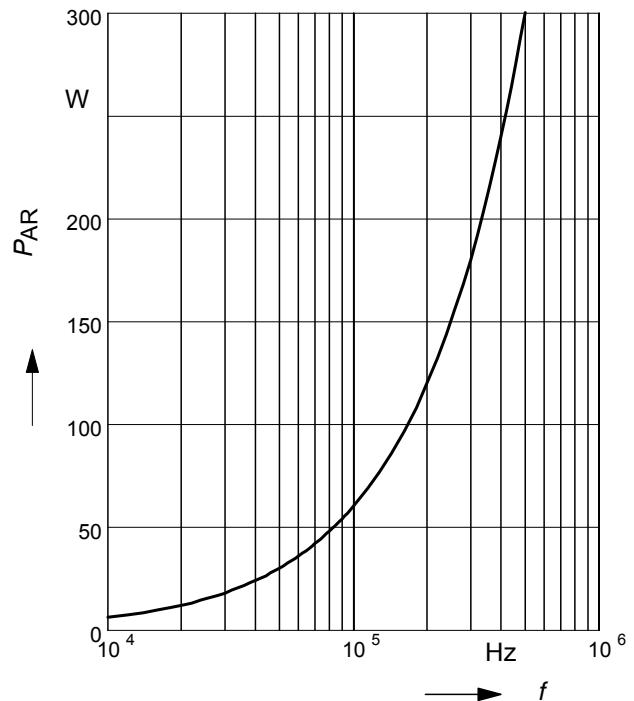
$$V_{(BR)DSS} = f(T_j)$$



### 14 Avalanche power losses

$$P_{AR} = f(f)$$

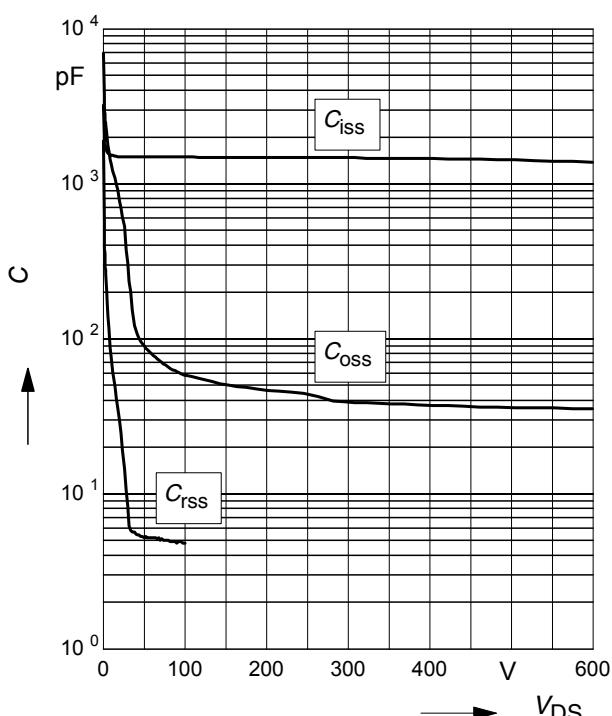
parameter:  $E_{AR}=0.6\text{mJ}$



### 15 Typ. capacitances

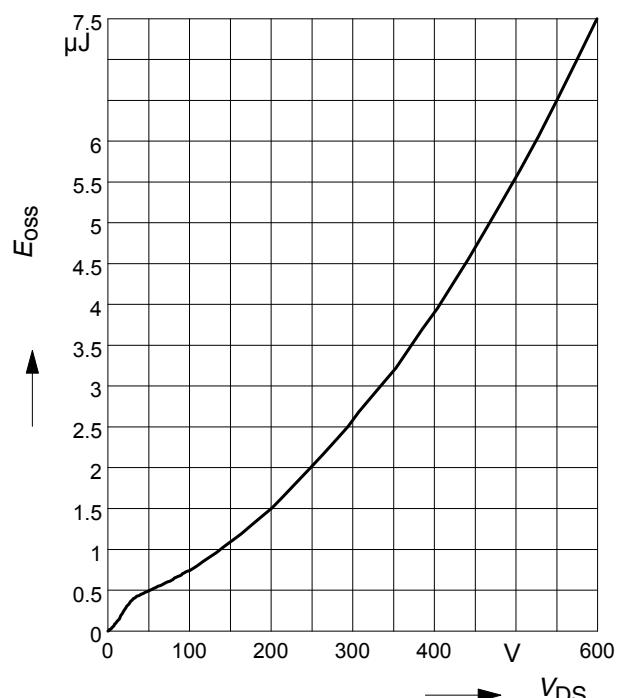
$$C = f(V_{DS})$$

parameter:  $V_{GS}=0\text{V}$ ,  $f=1\text{MHz}$

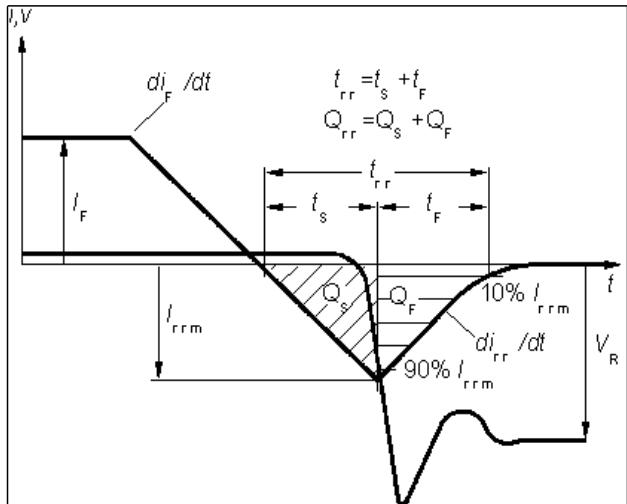


### 16 Typ. $C_{oss}$ stored energy

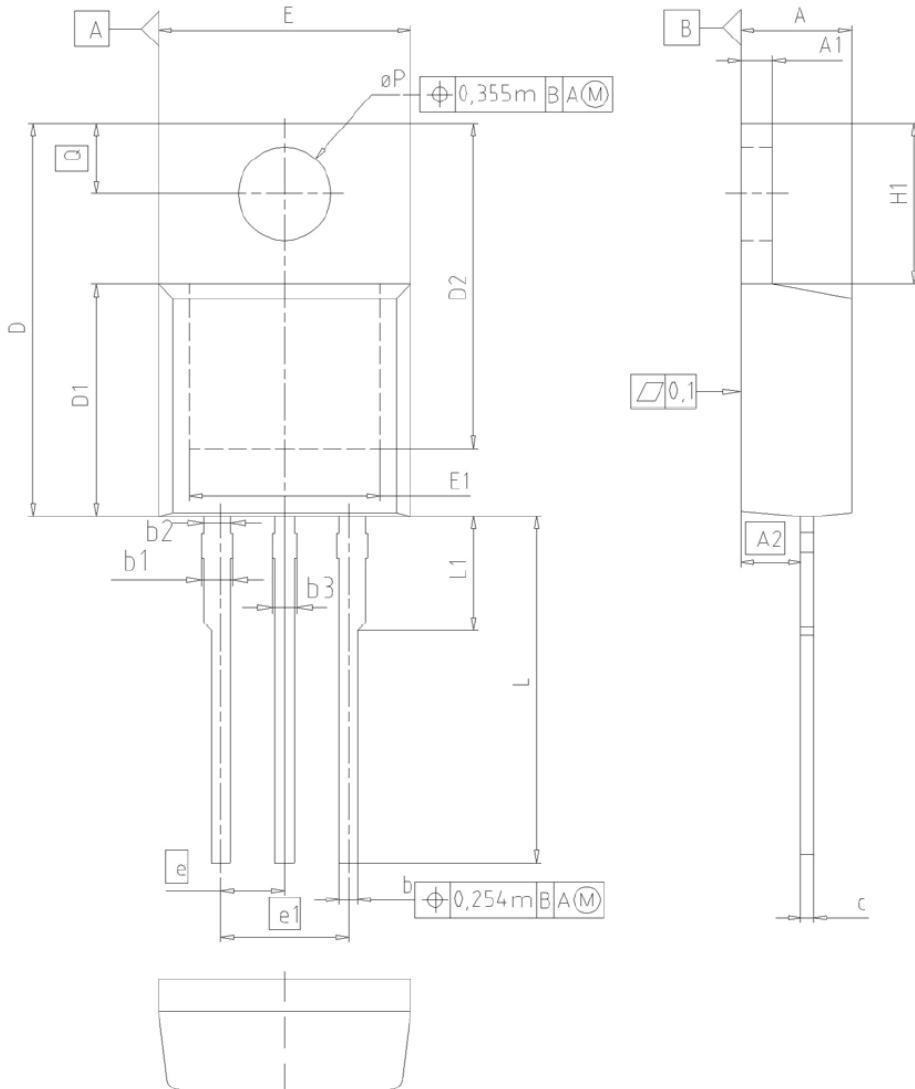
$$E_{oss}=f(V_{DS})$$



### Definition of diodes switching characteristics

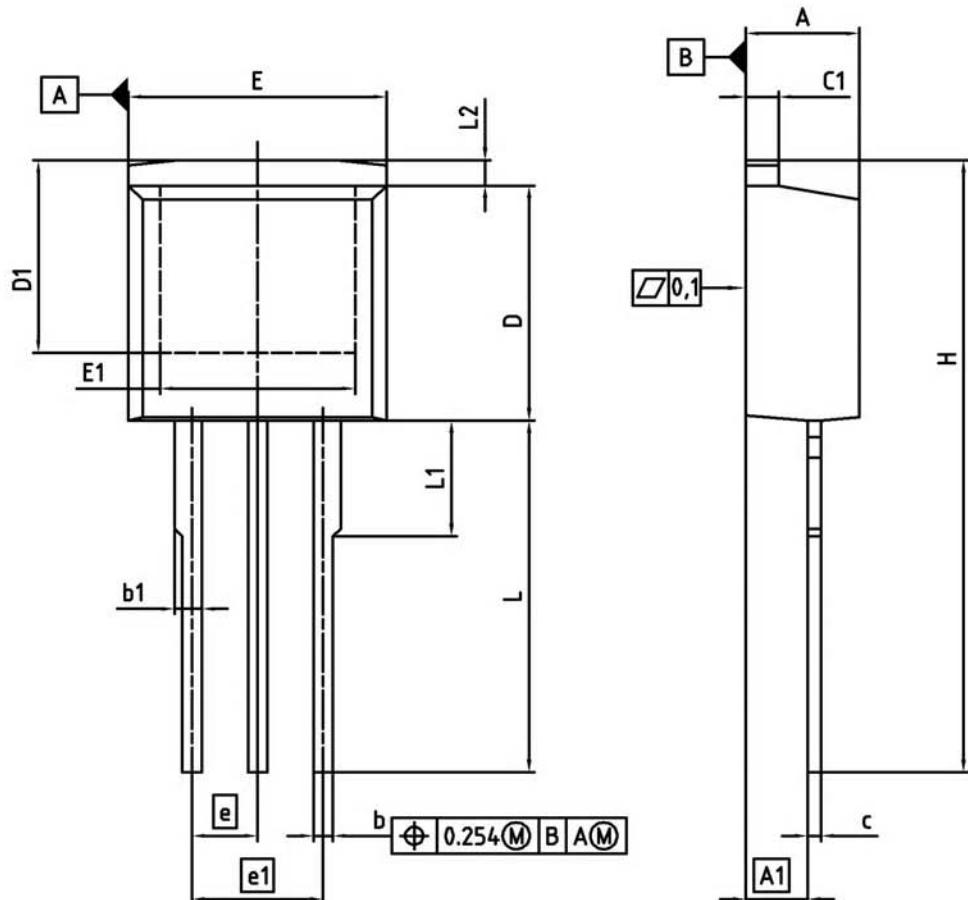


PG-T0220-3-1, PG-T0220-3-21



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
c	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
ØP	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

DOCUMENT NO.	Z8B00003318
SCALE	0 2.5 0 2.5 5mm
EUROPEAN PROJECTION	
ISSUE DATE	23-08-2007
REVISION	05

PG-T0262-3-1, PG-T0262-3-21 (I<sup>2</sup>-PAK)


DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.300	4.572	0.169	0.180
A1	2.150	2.718	0.085	0.107
b	0.650	0.864	0.026	0.034
b1	0.635	1.400	0.025	0.055
c	0.330	0.600	0.013	0.024
c1	1.170	1.400	0.046	0.055
D	8.509	9.450	0.335	0.372
D1	6.900	-	0.272	-
E	9.700	10.363	0.382	0.408
E1	6.500	8.600	0.256	0.339
e	2.540		0.100	
e1	5.080		0.200	
N	3		3	
L	13.000	14.000	0.512	0.551
L1	-	4.800	-	0.189
L2	-	1.727	-	0.068

REFERENCE JEDEC TO262
EUROPEAN PROJECTION 
ISSUE DATE 05-05-2006
FILE TO262_1



**SPP11N60S5  
SPI11N60S5**

---

**Published by**  
**Infineon Technologies AG**  
**81726 Munich, Germany**  
**© 2007 Infineon Technologies AG**  
**All Rights Reserved.**

**Legal Disclaimer**

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

**Information**

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office ([www.infineon.com](http://www.infineon.com)).

**Warnings**

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office.

Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.